

Is Now Part of



## **ON Semiconductor**®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor dates sheds, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheds and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use on similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor and its officers, employees, subsidiaries, affliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out or i, directly or indirectly, any lange of the applicatio customer's to unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the



### **FDD8880** N-Channel PowerTrench<sup>®</sup> MOSFET 30V, 58A, $9m\Omega$

### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $r_{\text{DS}(\text{ON})}$  and fast switching speed.

### Applications

DC/DC converters

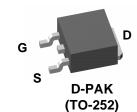


March 2015

FDD8880

### Features

- $r_{DS(ON)} = 9m\Omega$ ,  $V_{GS} = 10V$ ,  $I_D = 35A$
- $r_{DS(ON)} = 12m\Omega$ ,  $V_{GS} = 4.5V$ ,  $I_D = 35A$
- High performance trench technology for extremely low  ${\rm r}_{\rm DS(ON)}$
- · Low gate charge
- High power and current handling capability
- RoHS Compliant



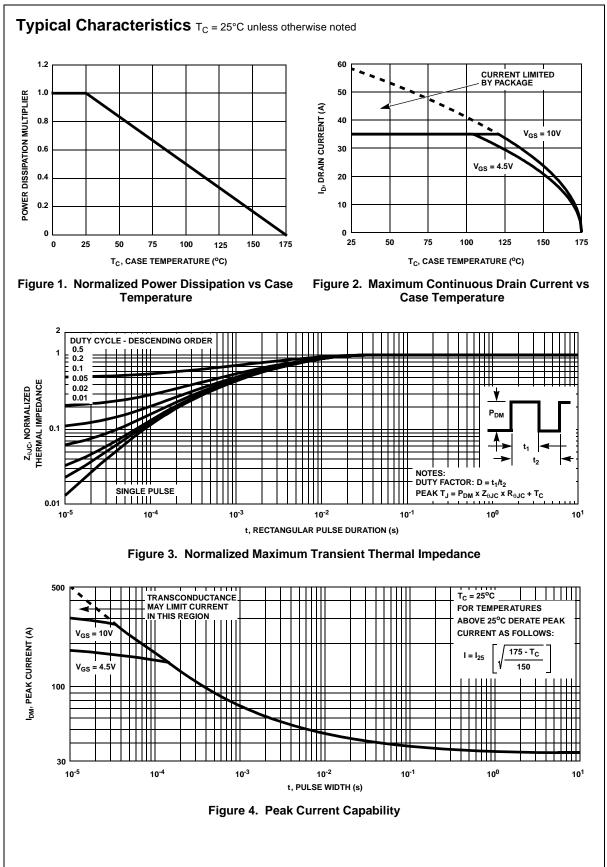


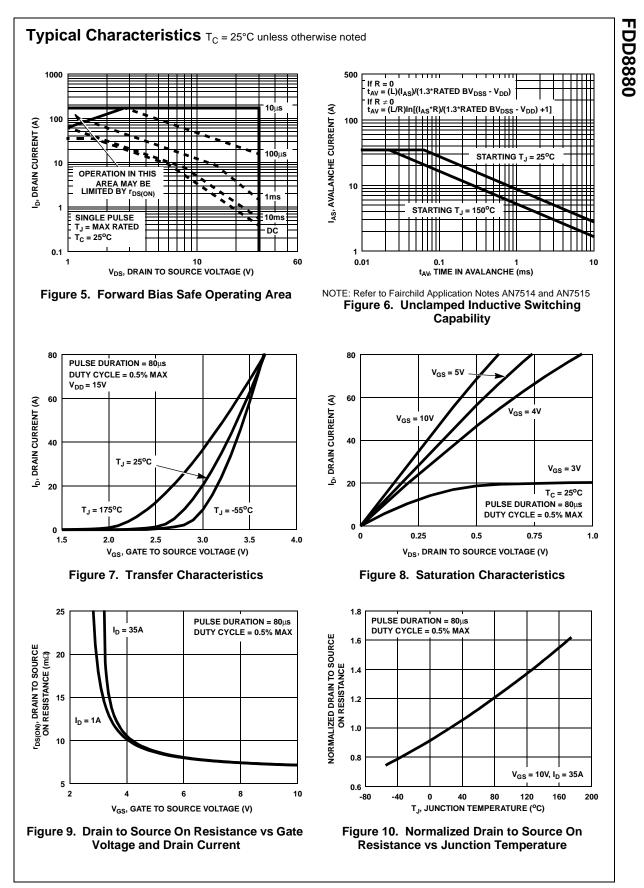
**MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter				Ratings	Units	
V <sub>DSS</sub>	Drain to Sou	Irce Voltage	30	V			
V <sub>GS</sub>	Gate to Sou	rce Voltage	±20	V			
Ι <sub>D</sub>	Drain Currer	nt					
	Continuous	(T <sub>C</sub> = 25 <sup>o</sup> C, V <sub>GS</sub> = 1	58	A			
	Continuous	(T <sub>C</sub> = 25 <sup>o</sup> C, V <sub>GS</sub> = 4	51	A			
	Continuous	$(T_{amb} = 25^{\circ}C, V_{GS} =$	13	A			
	Pulsed		Figure 4	A			
E <sub>AS</sub>	Single Pulse	e Avalanche Energy (	53	mJ			
P <sub>D</sub>	Power dissip	pation	55	W			
	Derate abov	re 25ºC	0.37	W/ºC			
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature				-55 to 175	5 °C	
R <sub>θJC</sub>	Charact	2.73	°C/M				
R <sub>θJA</sub>		sistance Junction to					
R <sub>θJA</sub>	Thermal Res	sistance Junction to	52	°C/W			
•		g and Orderin	•	1	Town Milalah	Quartitu	
Device Marking		Device	TO-252AA	Reel Size	Tape Width	Quantity	
FDD8880		FDD8880	10-252AA	13	16mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
Off Chara	acteristics						
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	30	-	-	V	
I <sub>DSS</sub>	-	$V_{\rm DS} = 24V$	-	-	1		
	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μA	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA	
	cteristics				•		
V <sub>GS(TH)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$		-	2.5	V	
<sup>v</sup> GS(TH) <sup>r</sup> DS(ON)		$I_D = 35A, V_{GS} = 10V$	1.2	0.007	0.009	19	
		$I_D = 35A, V_{GS} = 4.5V$	-	0.009	0.012		
	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$				Ω	
		$T_J = 175^{\circ}C$	-	- 0.013 0.015	0.015		
Dynamic	Characteristics						
C <sub>ISS</sub>	Input Capacitance		-	1260	-	pF	
C <sub>OSS</sub>	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$	-	260	-	pF	
C <sub>RSS</sub>	Reverse Transfer Capacitance	f = 1MHz	-	150	-	pF	
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 0.5V, f = 1MHz	-	2.3	-	Ω	
Q <sub>g(TOT)</sub>	Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V	-	23	31	nC	
Q <sub>g(5)</sub>	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$	-	13	17	nC	
Q <sub>g(TH)</sub>	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$ $V_{DD} = 15V$	-	1.3	1.7	nC	
Q <sub>gs</sub>	Gate to Source Gate Charge	$I_{D} = 35A$ $I_{a} = 1.0mA$	-	3.8	-	nC	
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau		-	2.5	-	nC	
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	5.0	-	nC	
Switching	g Characteristics (V <sub>GS</sub> = 10V)						
t <sub>ON</sub>	Turn-On Time		-	-	147	ns	
t <sub>d(ON)</sub>	Turn-On Delay Time	-	-	8	-	ns	
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15V, I <sub>D</sub> = 35A	-	91	-	ns	
t <sub>d(OFF)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 10\Omega$	-	38	-	ns	
t <sub>f</sub>	Fall Time		-	32	-	ns	
t <sub>OFF</sub>	Turn-Off Time		-	-	108	ns	
Drain-So	urce Diode Characteristics				•		
V <sub>SD</sub>		I <sub>SD</sub> = 35A	-	-	1.25	V	
	Source to Drain Diode Voltage	I <sub>SD</sub> = 15A	-	-	1.0	V	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 35A, dI <sub>SD</sub> /dt = 100A/µs		-	27	ns	
Q <sub>RR</sub>	Reverse Recovered Charge	I <sub>SD</sub> = 35A, dI <sub>SD</sub> /dt = 100A/µs	-	-	14	nC	

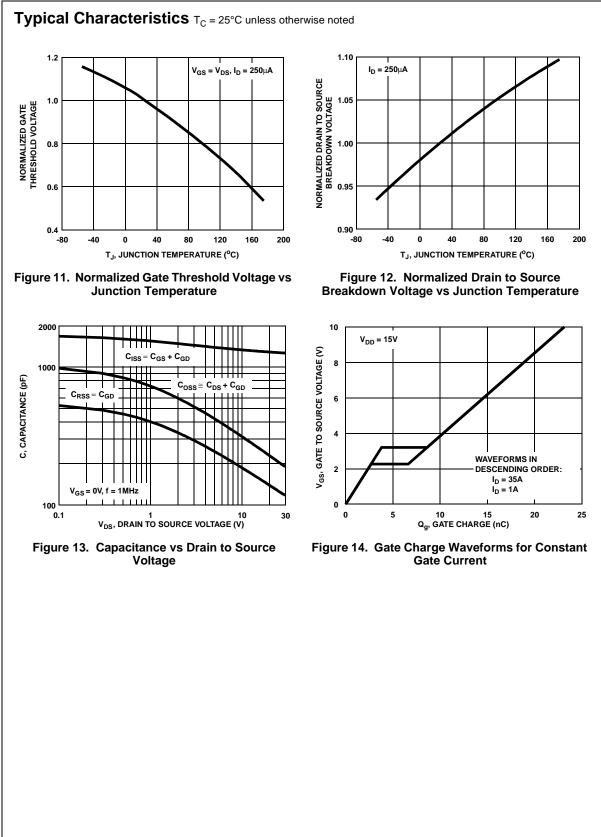






©2008 Fairchild Semiconductor Corporation

FDD8880 Rev. 1.2



# Test Circuits and Waveforms

Figure 15. Unclamped Energy Test Circuit

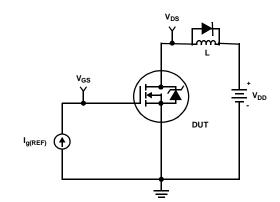


Figure 17. Gate Charge Test Circuit

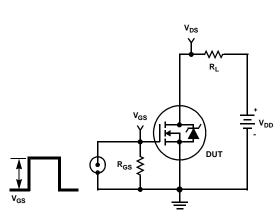
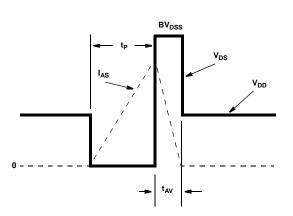
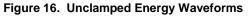


Figure 19. Switching Time Test Circuit





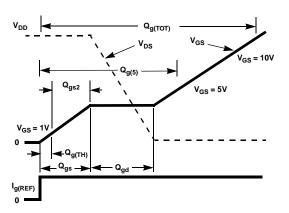
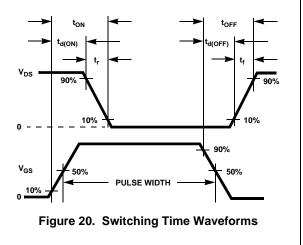


Figure 18. Gate Charge Waveforms



### Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A$  (°C), and thermal resistance  $R_{\theta JA}$  (°C/W) must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of  $P_{DM}$  is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the  $R_{\theta,JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

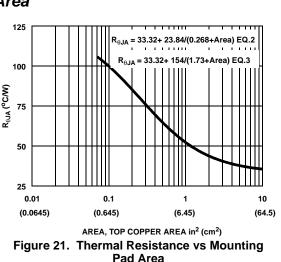
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

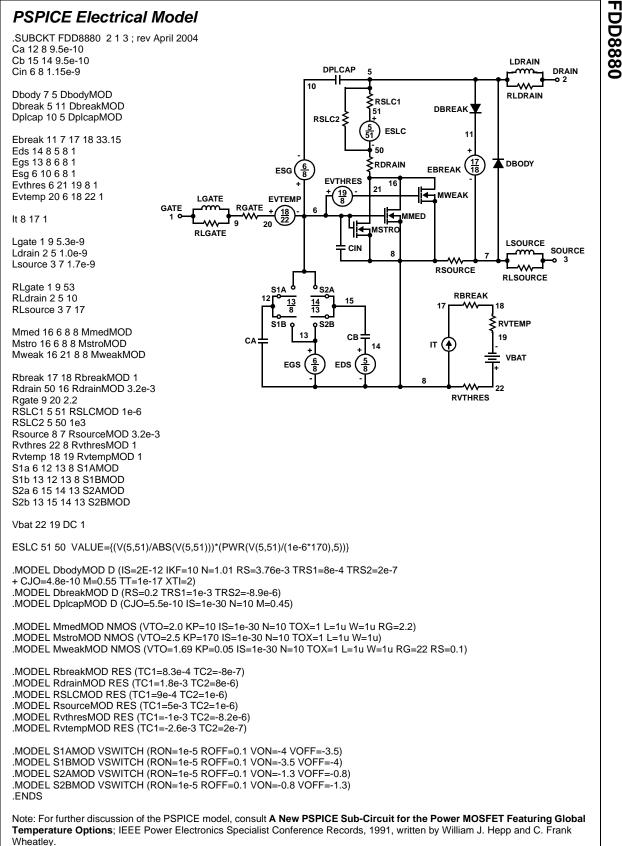
$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

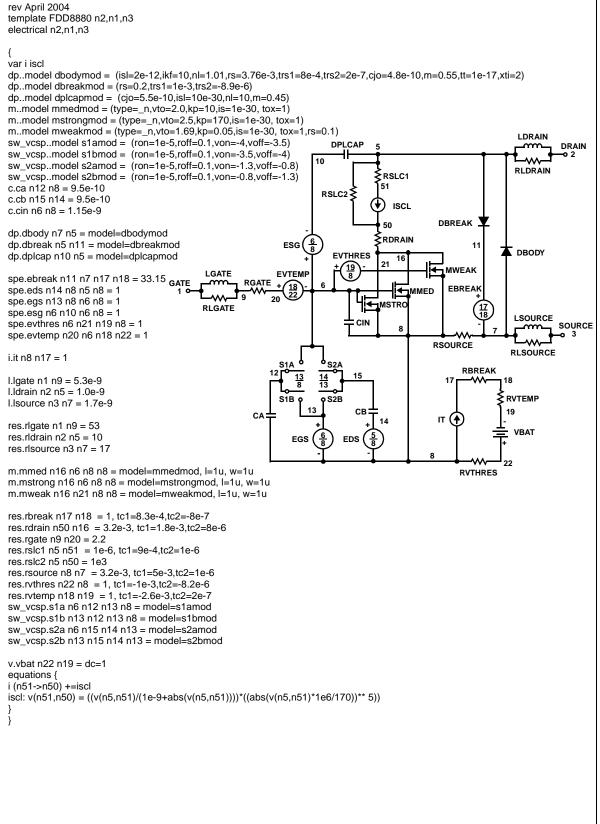
$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
(EQ. 3)

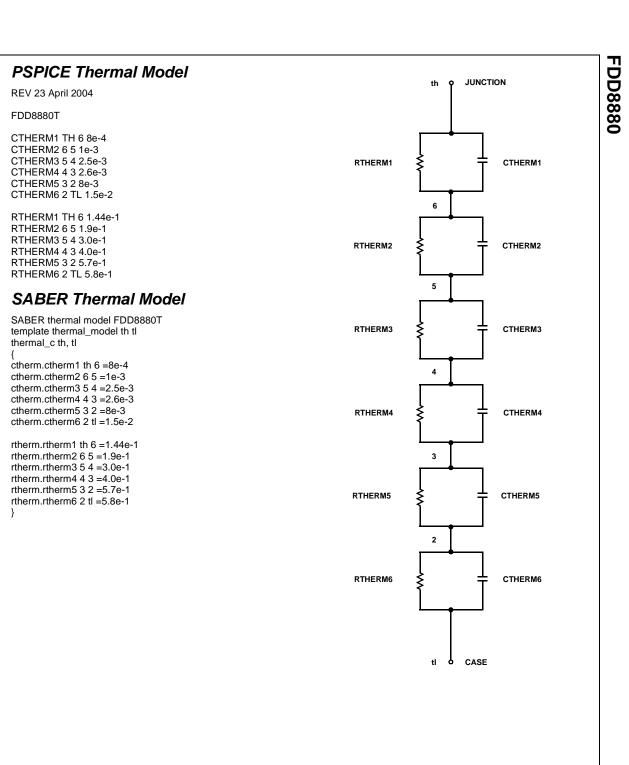
Area in Centimeters Squared





### SABER Electrical Model







ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor has against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death ass

### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5817-1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

© Semiconductor Components Industries, LLC